

Search Notes

Application/Control No.

10/761,080

Examiner

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Applicant(s)/Patent under
Reexamination

BEAUCHAMP, PHILLIP J.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	84	6/7/2006	BT
216	85	6/7/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search inventor's name and keywords using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/7/2006	BT